

Notice of References Cited

Application/Control No.

10/523,348

Applicant(s)/Patent Under
Reexamination
KOYANAGI ET AL.

Examiner

ADAM COONEY

Art Unit

2444

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,097,722	08-2000	Graham et al.	370/395.21
	B	US-			
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	L	US-			
	M	US-			

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.